

TEST REPORT

APPLICANT : SAMSUNG ELECTRONICS Co., Ltd.
ADDRESS : 1, Samsungjeonja-ro,
Hwaseong-si, Gyeonggi-do, Korea

PAGE: 1 of 5

REPORT NO. RT22R-S0390-004-E3

DATE: Feb. 04, 2022

SAMPLE DESCRIPTION : The following submitted sample(s) said to be:-

NAME/TYPE OF PRODUCT : 12inch wafer (No C/F, No Bump)

SAMPLE ID NO. : RT22R-S0390-004

MANUFACTURER/VENDOR : SAMSUNG ELECTRONICS Co., Ltd.

SAMPLE RECEIVED : Jan. 19, 2022

TESTING DATE : Jan. 19, 2022 ~ Feb. 04, 2022

TEST METHOD(S) : Please see the following page(s).

TEST RESULT(S) : Please see the following page(s).

* Note 1 : The test results presented in this report refer only to the object tested.

* Note 2 : This report shall not be reproduced except in full without the written approval of the testing laboratory.

Approved by,



Jade Jang / Lab. Technical Manager

Authorized by,



Bo Park / Lab. General Manager



Authenticity check

Intertek Testing Services Korea Ltd.

Seoul Office: Tel : 02-6090-9500 Fax : 02-3409-0025 Web Site : intertek.co.kr

Seoul Lab. Address : 7, Ahasan-ro 5-gil, Seongdong-gu, Seoul, 04793 Korea

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PAGE: 2 of 5
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SAMPLE ID NO. : RT22R-S0390-004
SAMPLE DESCRIPTION : 12inch wafer (No C/F, No Bump)

TEST ITEM	UNIT	TEST METHOD	MDL	RESULT
Beryllium (Be)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.
Cobalt (Co)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.
Indium (In)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.
Nickel (Ni)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.
Phosphorus (P)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.
Antimony (Sb)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.
Tin (Sn)	mg/kg	With reference to US EPA 3052, by acid digestion and determined by ICP-OES	2	N.D.

Tested by : Chano Kim, Jooyeon Lee

Notes : mg/kg = ppm = parts per million
< = Less than
N.D. = Not detected (<MDL)
MDL = Method detection limit

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PAGE: 3 of 5
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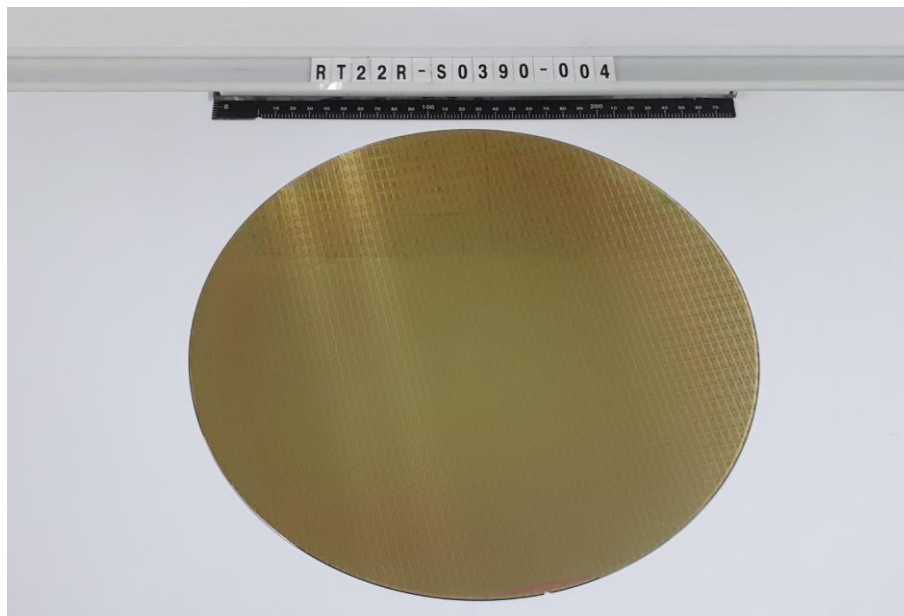
SAMPLE ID NO. : RT22R-S0390-004
SAMPLE DESCRIPTION : 12inch wafer (No C/F, No Bump)

TEST ITEM	UNIT	TEST METHOD	MDL	RESULT
Tetrabromobisphenol-A (TBBP-A)	mg/kg	With reference to US EPA 3540C, by solvent extraction and determined by LC/MS/MS	5	N.D.
Medium-chain chlorinated paraffin (MCCP)	mg/kg	With reference to US EPA 3540C, by solvent extraction and determined by LC/MS/MS and/or GC/ECD	100	N.D.

Tested by : Hayan Park

Notes : mg/kg = ppm = parts per million
< = Less than
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* View of sample as received;-



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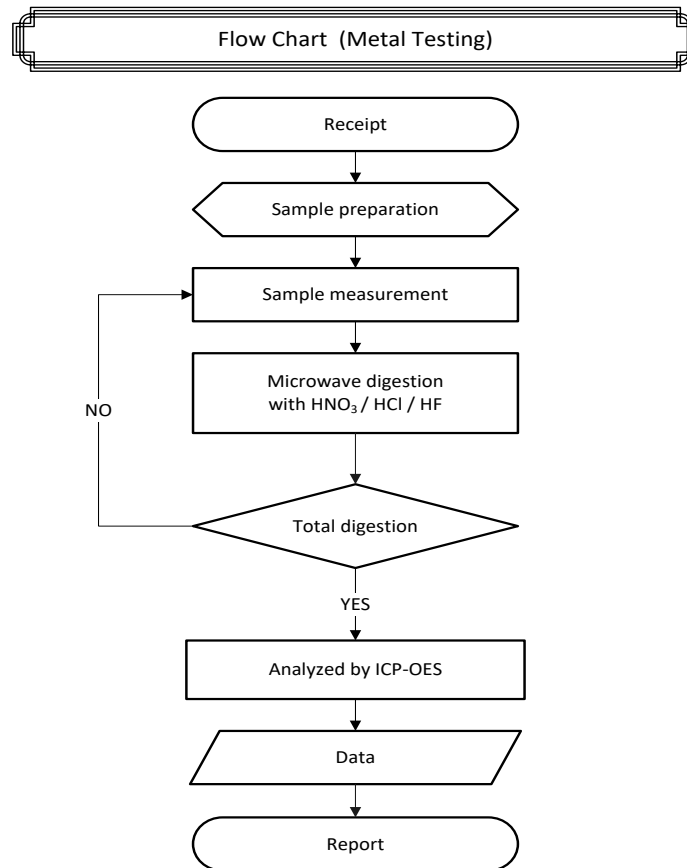
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** Remarks : The samples were dissolved totally by pre-conditioning method according to above flow chart.



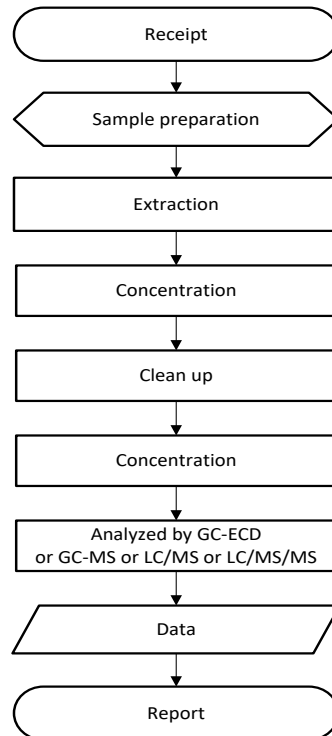
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Flow Chart (EPA 3540C)



***** End of Report *****

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